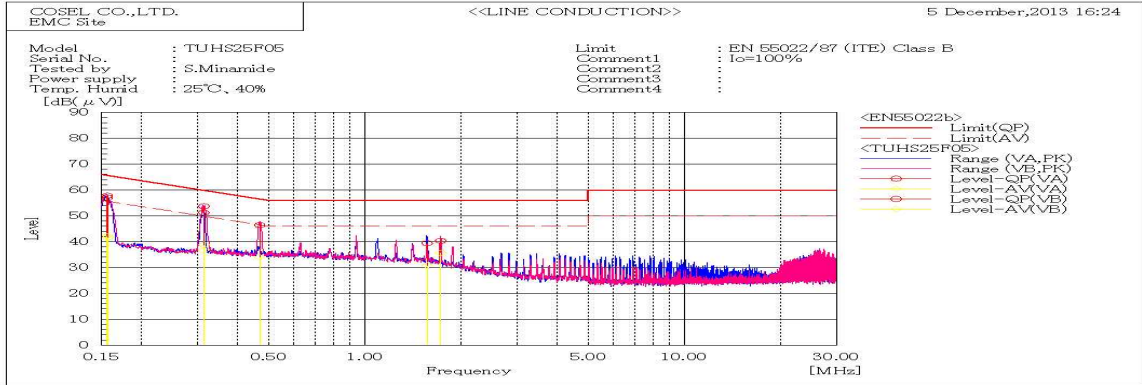
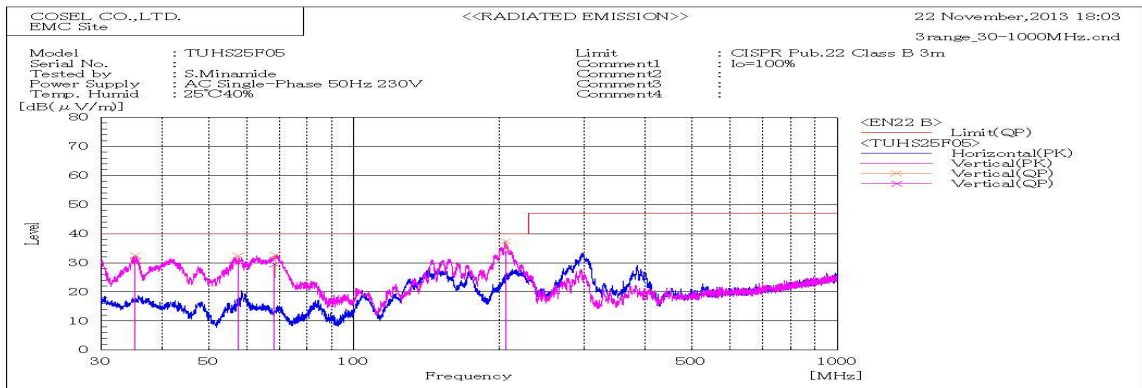


DATA SHEET		Date	16-Dec-13
Model	TUHS25F05	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide



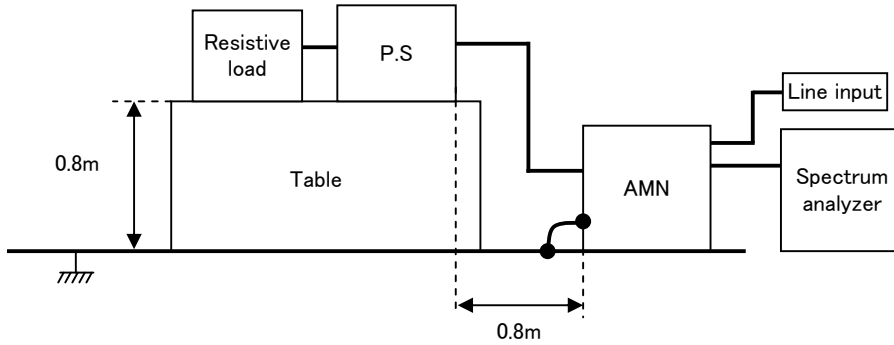
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.15664		VA	36.9	21.3	20.2	57.1	41.5	65.6	55.6	8.5	8.5	Pass	
0.15646		VB	37.6	22.1	20.2	57.8	42.3	65.6	55.6	7.8	7.8	Pass	
0.31416		VB	33.6	18.7	20.1	53.7	38.8	59.9	49.9	6.2	6.2	Pass	
0.31376		VA	31.1	16.5	20.1	51.2	36.6	59.9	49.9	8.7	8.7	Pass	
0.46949		VB	26.3	13.9	20.1	46.4	34	56.5	46.5	10.1	10.1	Pass	
1.56651		VA	19.1	10.5	20.3	39.4	30.8	56	46	16.6	16.6	Pass	
1.72941		VB	20.1	15.5	20.2	40.3	35.7	56	46	15.7	15.7	Pass	



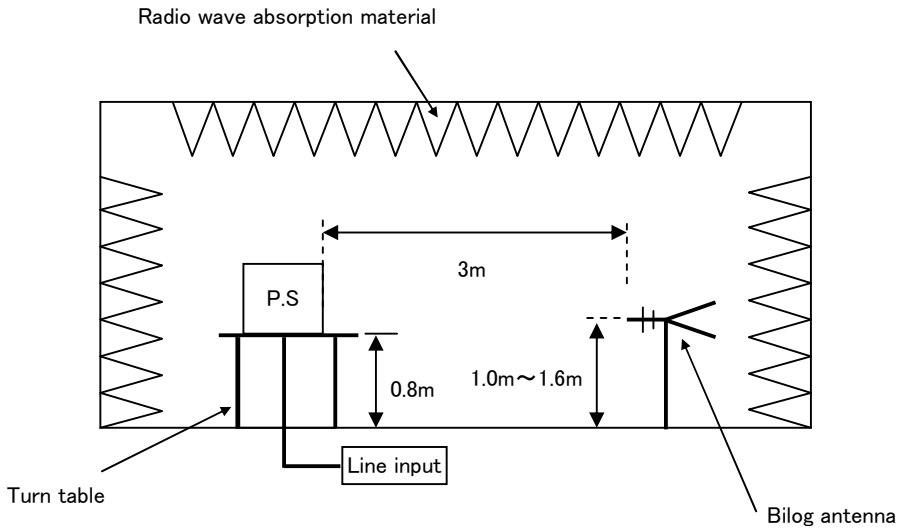
Frequency MHz	Polarization	Stability	Reading dB(uV)		Factor dB(1/m)	Level dB(uV/m)		Limit dB(uV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP			QP	QP						
35.265	V	Stable	45.4		-14.8	30.6		40	9.4	Pass	102	43	
57.721	V	Stable	54.1		-24	30.1		40	9.9	Pass	104	73	
68.546	V	Stable	50.3		-20.8	29.5		40	10.5	Pass	136	69	
206.089	V	Stable	48.8		-15.3	33.5		40	6.5	Pass	102	316	

DATA SHEET		Date	16-Dec-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide

1. Line conduction



2. Radiated emission



Conditions

Test: EMI
 Model Name: TUHS25F□□

- Photographs of Test Set-Up

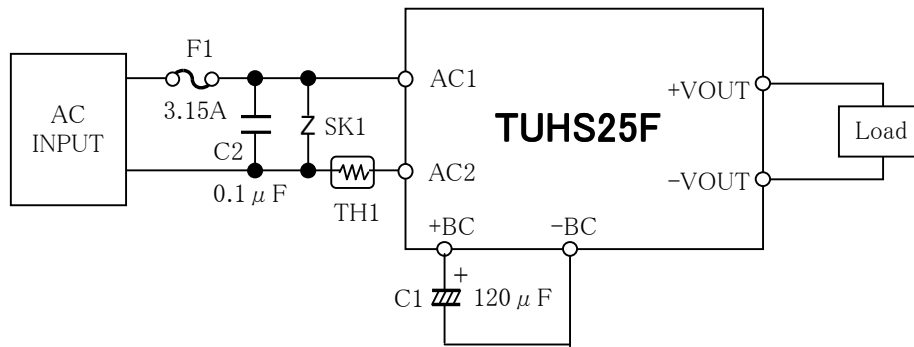
LINE CONDUCTION



RADIATED EMISSION



- Test circuit



F1:	SLT250V3.15A (Nippon Seisen)	3.15A
TH1:	10D2-08LCS (SEMITEC)	10Ω
SK1:	S10K385E2K1 (TDK EPCOS)	

Fig.1 Testing circuitry